

Advanced Tools for Nanoscale Materials Characterization

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Systems for Research (SFR) is a Canadian company that has been exclusively serving Canadian universities, industry, and health science institutions for over 25 years, offering an array of cutting-edge scientific instrumentation. This presentation will provide an overview of our advanced tools for nanoscale characterization, with a special focus on three distinct technologies: desktop scanning electron microscopy (SEM), mass photometry, synchrotron-in-the-lab x-ray instrumentation.

Bio:

Dr. David Polcari obtained a Ph.D. in Chemistry from McGill University in 2017, under the supervision of Prof. Janine Mauzeroll. His doctoral research focused on the use of scanning electrochemical microscopy (SECM) and bioelectrochemistry for the investigation of live cell processes. He then completed a postdoctoral fellowship at UQAM with Prof. Steen Schougaard, focusing on the characterization of Li-ion battery materials. He joined Systems for Research in 2018 and is currently the business manager for Quebec and Atlantic Canada.